

### **Description**

The AOD607-HXY uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

# D1/D2 PIT M5/FF S1 G1

TO252-4L

#### **General Features**

 $V_{DS} = 30V I_{D} = 20A$ 

 $R_{DS(ON)}$  < 24m $\Omega$  @  $V_{GS}$ =10V

 $V_{DS} = -30V I_{D} = -20A$ 

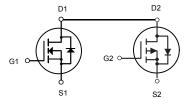
 $R_{DS(ON)} < 40 \, m\Omega$  @  $V_{GS}$ =-10V

# **Application**

Wireless charging

Boost driver

Brushless motor



N-Channel MOSFET

P-Channel MOSFE

# **Package Marking and Ordering Information**

	<u> </u>		
Product ID	Pack	Marking	Qty(PCS)
AOD607-HXY	TO252-4L	3012 XXXX	2500

### Absolute Maximum Ratings (T<sub>C</sub>=25<sup>°</sup>Cunless otherwise noted)

	P	Rati	ng	11.24.
Symbol	Parameter	N-Channel	P-Channel	Units
VDS	Drain-Source Voltage	30	-30	V
VGS	Gate-Source Voltage	±20	±20	V
I <sub>D</sub> @T <sub>A</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	20	-20	Α
I <sub>D</sub> @T <sub>A</sub> =70 ℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	15	-14	Α
IDM	Pulsed Drain Current <sup>2</sup>	50	-50	Α
EAS	Single Pulse Avalanche Energy <sup>3</sup>	26.6	110	mJ
IAS	Avalanche Current	12.7	-30	Α
P <sub>D</sub> @T <sub>A</sub> =25℃	Total Power Dissipation <sup>4</sup>	20.8	20.8	W
TSTG	Storage Temperature Range	-55 to 150	-55 to 150	$^{\circ}$
TJ	Operating Junction Temperature Range	-55 to 150	-55 to 150	$^{\circ}\!\mathbb{C}$
R₀JA	Thermal Resistance Junction-Ambient <sup>1</sup>	6.	2	°C/W
R₀JC	Thermal Resistance Junction-Case <sup>1</sup>	6	;	°C/W



# N-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.023		V/°C
В	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =10A		16	24	0
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =6A		25	30	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V V I 250	1.0		2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=250uA$		-4.2		mV/°C
1	Drain Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =10A		14		S
$R_g$	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		2.3		Ω
$Q_g$	Total Gate Charge (4.5V)			5		
$Q_gs$	Gate-Source Charge	$V_{DS}$ =20V , $V_{GS}$ =4.5V , $I_{D}$ =10A		1.11		nC
$Q_gd$	Gate-Drain Charge			2.61		
T <sub>d(on)</sub>	Turn-On Delay Time			7.7		
Tr	Rise Time	$V_{DD}$ =12V , $V_{GS}$ =10V , $R_{G}$ =3.3 $\Omega$		46		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =6A		11		ns
T <sub>f</sub>	Fall Time			3.6		
Ciss	Input Capacitance			416		
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		62		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			51		

#### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,5</sup>	V V OV Force Current			24	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			50	Α
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V

#### Note:

<sup>1.</sup> The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

<sup>2.</sup>The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

<sup>3.</sup> The EAS data shows Max. rating . The test condition is  $V_{DD}$ =25V,  $V_{GS}$ =10V,L=0.1mH,I<sub>AS</sub>=12.7A

<sup>4.</sup>The power dissipation is limited by 150°C junction temperature

<sup>5.</sup> The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



# P-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-30			V
$\triangle BV_{DSS}/\triangle T_J$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =-1mA		-0.021		V/°C
В	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-8A		37	40	0
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-6A		45	53	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V V I 050	-1.0		-2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=-250uA$		-4.2		mV/°C
1	Drain Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}=\pm 20V$ , $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-8A		12.6		S
$R_g$	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		15		Ω
$Q_g$	Total Gate Charge (-4.5V)			9.8		
$Q_{gs}$	Gate-Source Charge	$V_{DS}$ =-20V , $V_{GS}$ =-4.5V , $I_{D}$ =-6A		2.2		nC
$Q_gd$	Gate-Drain Charge			3.4		
T <sub>d(on)</sub>	Turn-On Delay Time			16.4		
T <sub>r</sub>	Rise Time	$V_{DD}$ =-24V , $V_{GS}$ =-10V , $R_{G}$ =3.3 $\Omega$ ,		20.2		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =-1A		55		ns
T <sub>f</sub>	Fall Time			10		
C <sub>iss</sub>	Input Capacitance			930		
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1MHz		148		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			115		

## **Diode Characteristics**

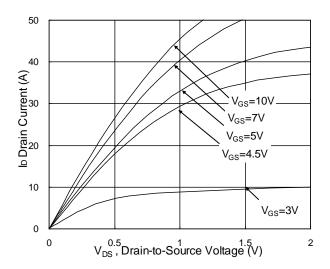
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,5</sup>	V V OV Force Current			-22	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-50	Α
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1.2	V

#### Note:

- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- 3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =-25V,  $V_{GS}$ =-10V, L=0.1mH,  $I_{AS}$ =-30A
- 4.The power dissipation is limited by 150°C junction temperature
- 5. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



# **N-Channel Typical Characteristics**



**Fig.1 Typical Output Characteristics** 

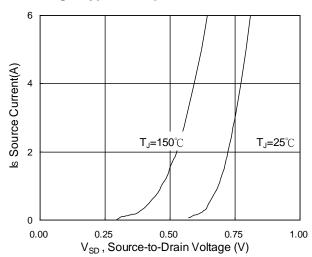


Fig.3 Forward Characteristics Of Reverse

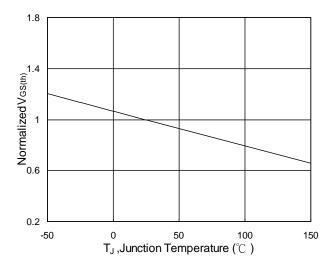


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$ 

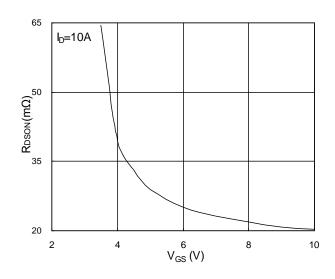


Fig.2 On-Resistance vs. Gate-Source

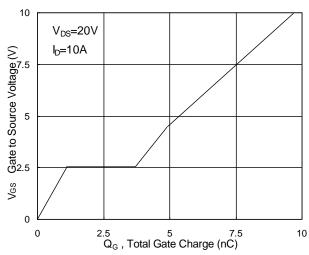


Fig.4 Gate-Charge Characteristics

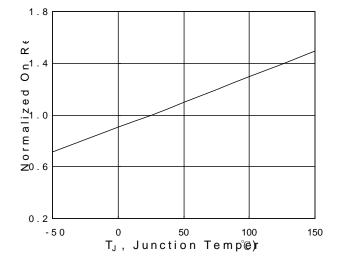
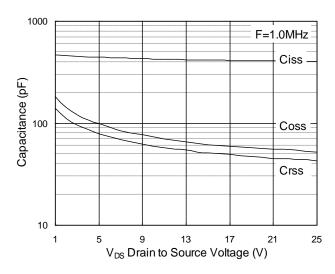


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>



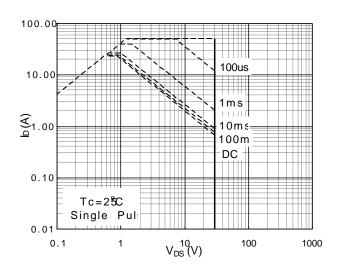


Fig.7 Capacitance Fig.8 Safe Operating Area Normalized Thermal Response (Reuc) DUTY=0.5 0.2 0.1 0.1 0.05 0.02 0.01  $T_{Jpeak} = T_C + P_{DM}XR_{\theta JC}$ SINGLE 0.01 0.00001 0.0001 0.001 0.01 0.1 10 t, Pulse Width (s)

Fig.9 Normalized Maximum Transient Thermal Impedance

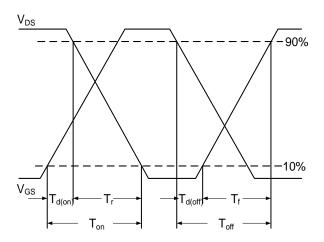


Fig.10 Switching Time Waveform

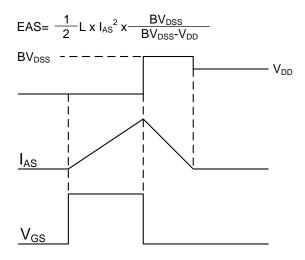


Fig.11 Unclamped Inductive Switching Waveform



# **P-Channel Typical Characteristics**

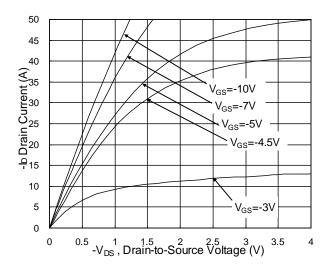


Fig.1 Typical Output Characteristics

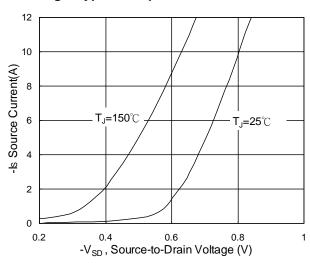


Fig.3 Forward Characteristics Of Reverse

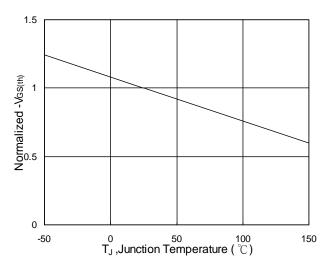


Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$ 

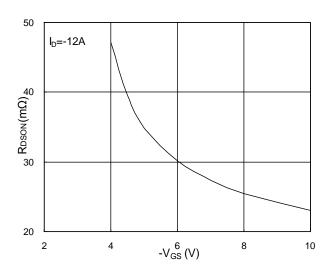


Fig.2 On-Resistance v.s Gate-Source

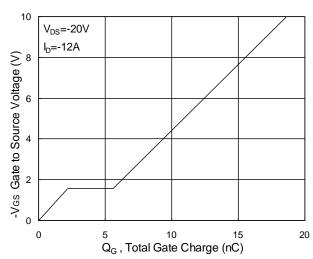


Fig.4 Gate-Charge Characteristics

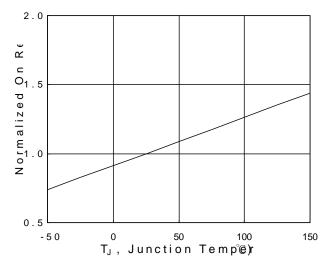
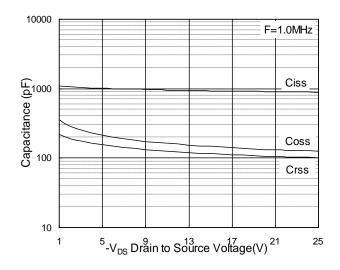


Fig.6 Normalized R<sub>DSON</sub> v.s T<sub>J</sub>





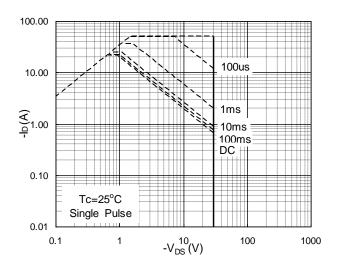


Fig.7 Capacitance

Fig.8 Safe Operating Area

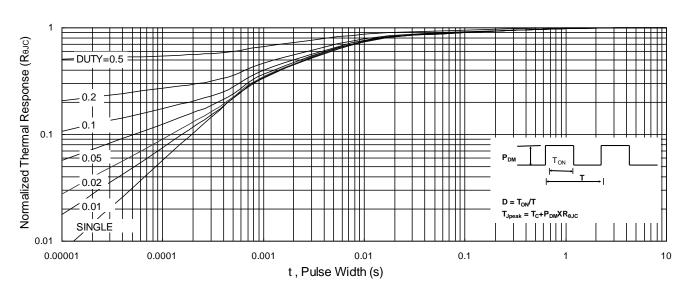
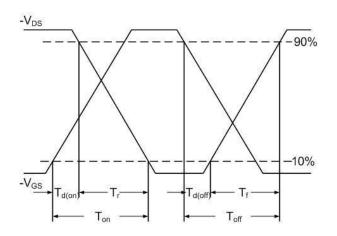


Fig.9 Normalized Maximum Transient Thermal Impedance





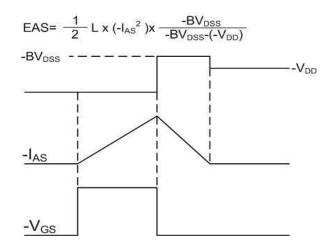
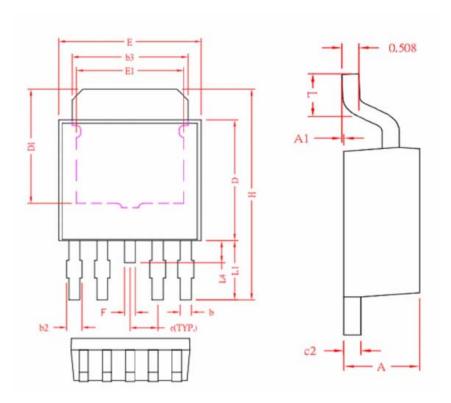


Fig.11 Unclamped Inductive Switching Waveform



# **TO252-4L Package Information**



SYMBOL	MIN	NOM	MAX
A	2.20	2.30	2.40
A1	0	0.08	0.15
ь	0.45	0.53	0.60
b2	0.50	0.65	0.80
b3	5.20	5. 35	5.50
c2	0.45	0.50	0.55
D	5.40	5. 60	5.80
D1	4.57	-	
E	6.40	6.60	6.80
E1	3.81	-	-
е	1	. 27 REF	
F	0.40	0.50	0.60
Н	9.40	9.80	10.20
L	1.40	1.59	1.77
L1	2.40	2.70	3,00
L4	0.80	1.00	1.20



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